

TS75N09A

90A 65V N-Channel Enhancement Mode Power Mosfet

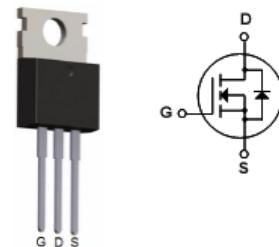
Features

- ◆ 90A,65V, $R_{DS(on)}=6.8m\Omega$ @ $V_{GS}=10V$
- ◆ Special process technology for high ESD capability
- ◆ High density cell design for ultra low $R_{DS(on)}$
- ◆ Fully characterized Avalanche voltage and current
- ◆ Good stability and uniformity with high E_{AS}
- ◆ Excellent package for good heat dissipation

General Description

- ◆ Package:TO-220C
- ◆ The TS75N09A uses advanced trench technology and design to provide excellent $T_{DS(on)}$ with low gate charge. It can be used in a wide variety of applications.

Absolute Maximum Ratings($T_c=25^{\circ}C$ unless otherwise noted)



| Symbol | Parameter | Spec | Units |
|----------------|--|-------------|----------------|
| V_{DSS} | Drain-Source Voltage | 65 | V |
| I_D | Drain Current -Continuous($T_c=25^{\circ}C$) | 90 | A |
| I_D | Drain Current -Continuous($T_c=100^{\circ}C$) | 63 | A |
| I_{DM} | Drain Current -Pulsed | 300 | A |
| V_{GSS} | Gate-Source Voltage | ± 25 | V |
| P_D | Maximum Power Dissipation | 160 | W |
| | Derating factor | 1.07 | W/ $^{\circ}C$ |
| E_{AS} | Single Pulsed Avalanche Energy (Note 5) | 550 | mJ |
| T_J, T_{DTG} | Operating Junction and Storage Temperature Range | -55 to +175 | $^{\circ}C$ |
| R_{JC} | Thermal Resistance,Junction-to-Case (Note 2) | 0.94 | $^{\circ}C/W$ |

Electrical Characteristics($T_c=25^{\circ}C$ unless otherwise noted)

Off Characteristics

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|------------|---------------------------------|-----------------------------|-----|-----|-----------|---------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_D=250\mu A$ | 65 | 68 | — | V |
| I_{BS} | Zero Gate Voltage Drain Current | $V_{DS}=65V, V_{GS}=0V$ | — | — | 1 | μA |
| I_{GS} | Gate-Body Leakage Current, | $V_{GS}=\pm 20V, V_{DS}=0V$ | — | — | ± 100 | nA |

On Characteristics (Note 3)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|--------------|-----------------------------------|-------------------------------|-----|-----|-----|-----------|
| V_{GSTH} | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu A$ | 2.0 | 3.0 | 4.0 | V |
| $R_{DS(on)}$ | Static Drain-Source On-Resistance | $V_{GS}=10V, I_D=40A$ | — | 6.8 | 8 | $m\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=5V, I_D=40A$ | 60 | - | - | S |

Dynamic Characteristics (Note 4)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|------------------|------------------------------|---|-----|------|-----|-------|
| C _{jss} | Input Capacitance | V _{DS} =30V,V _{GS} =0V,f=1.0MHz | — | 3590 | — | pF |
| C _{oss} | Output Capacitance | | — | 371 | — | pF |
| C _{rss} | Reverse Transfer Capacitance | | — | 258 | — | pF |

Switching Characteristics (Note 4)

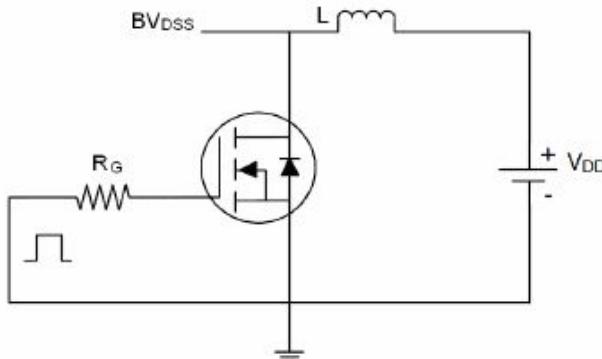
| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|---------------------|---------------------|---|-----|------|-----|-------|
| t _{d(on)} | Turn-On Delay Time | V _{DD} =30V I _D =30A R _G =6.8Ω V _{GS} =10V | — | 18 | — | ns |
| t _r | Turn-On Rise Time | | — | 120 | — | ns |
| t _{d(off)} | Turn-Off Delay Time | | — | 55 | — | ns |
| t _f | Turn-Off Fall Time | | — | 68 | — | ns |
| Q _g | Total Gate Charge | V _{DS} =30V I _D =30A V _{GS} =10V | — | 73 | — | nc |
| Q _{gs} | Gate-Source Charge | | — | 16.6 | — | nc |
| Q _{gd} | Gate-Drain Charge | | — | 26 | — | nc |

Drain-Source Diode Characteristics and Maximum Ratings

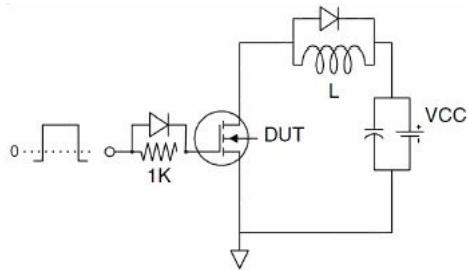
| Symbol | Parameter | Test Conditions | Min | Typ | Max | Units |
|-----------------|--------------------------------|---|-----|-----|-----|-------|
| I _s | diode forward current (Note 3) | | — | — | 78 | A |
| V _{sd} | diode forward Voltage (Note 2) | V _{GS} =0V,I _S =20A | — | — | 1.2 | V |
| T _{rr} | Reverse Recovery Time | T _J =25 °C,I _S =30A | — | 45 | — | ns |
| Q _{rr} | Reverse Recovery charge | dif/dt=100A/us (Note 3) | — | 76 | — | uc |
| T _{on} | Forward Turn-On Time | Intrinsic turn-on time is negligible(turn-on is dominated by LS+LD) | | | | |

Notes:

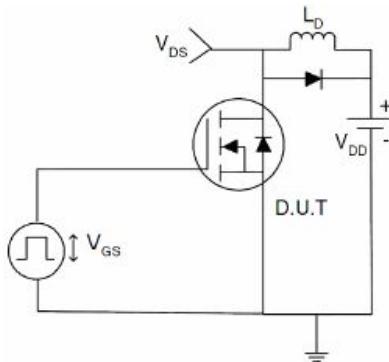
- 1.Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2.Surface Mounted on FR4 Board, t≤10 sec
- 3.Pulse Test: Pulse Width ≤300us,Duty cycle≤2%
- 4.Guaranteed by design, not subject to production
- 5.EAS condition: T_j=25 °C,V_{DD}=30V,V_G=10V,L=0.5mH,R_g=25Ω

Test circuits
1)EAS Test Circuits


2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical And Thermal Characteristics(Curves)

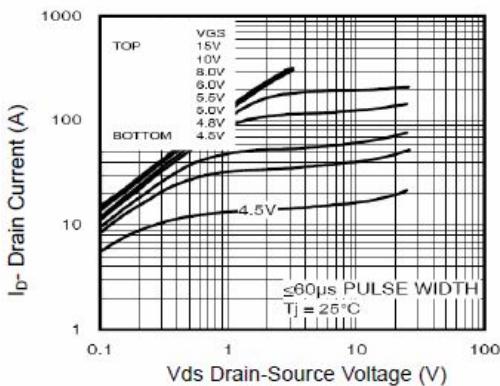


Figure 1 Output Characteristics

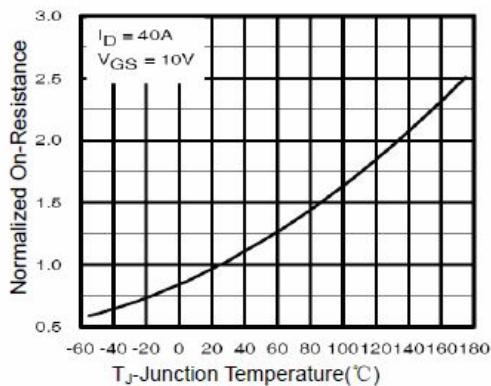


Figure 4 Rdson-JunctionTemperature

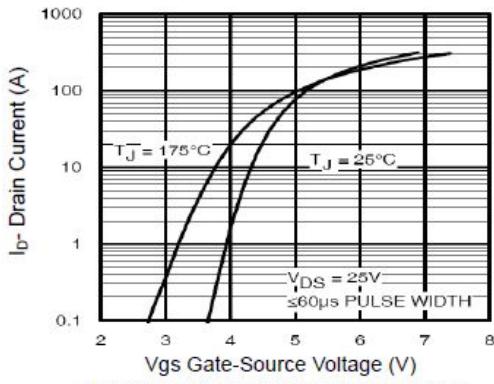


Figure 2 Transfer Characteristics

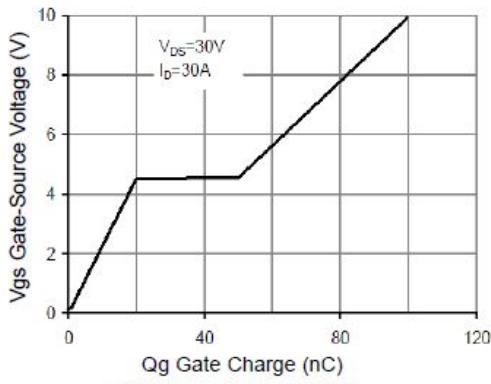


Figure 5 Gate Charge

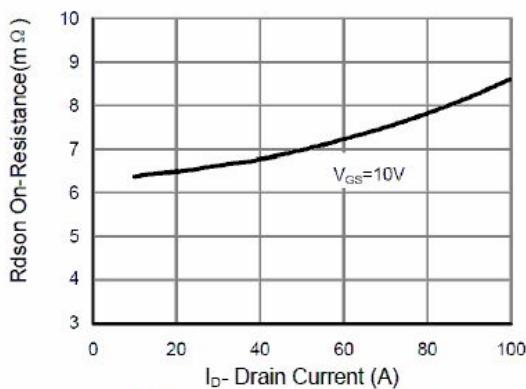


Figure 3 Rdson- Drain Current

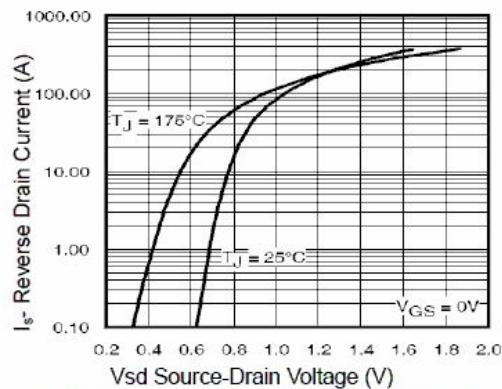


Figure 6 Source- Drain Diode Forward

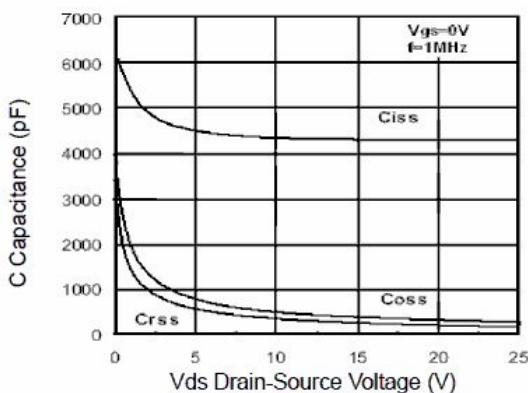


Figure 7 Capacitance vs Vds

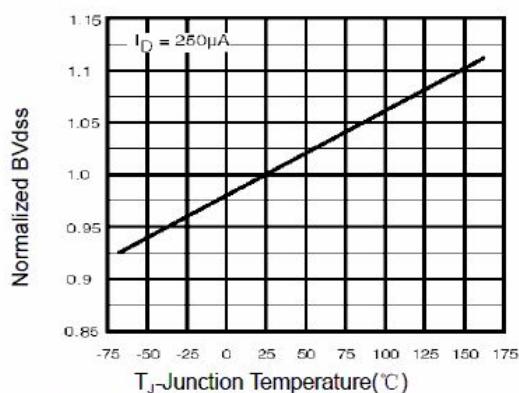


Figure 9 BV_{DSS} vs Junction Temperature

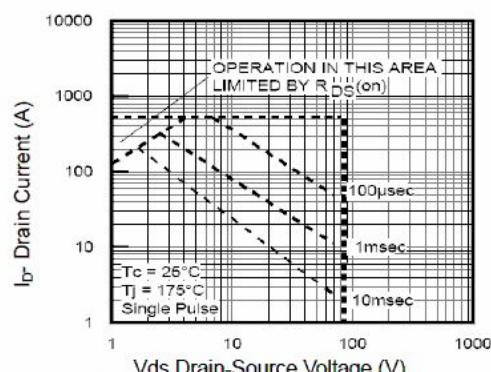


Figure 8 Safe Operation Area

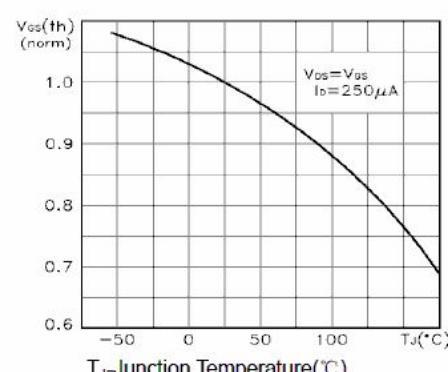


Figure 10 V_{GS(th)} vs Junction Temperature

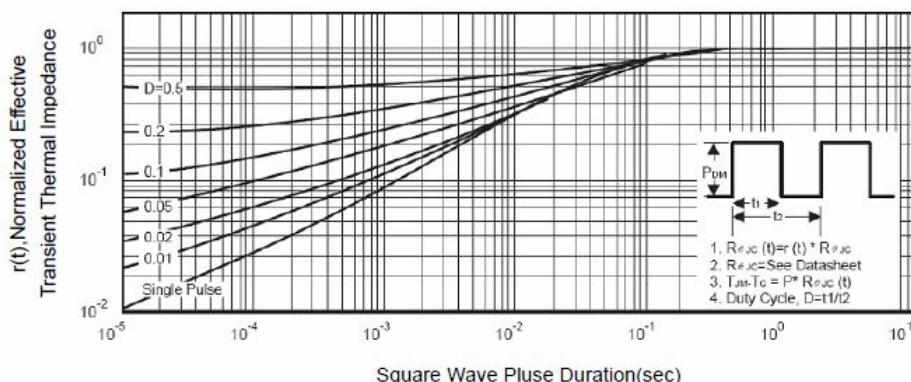


Figure 11 Normalized Maximum Transient Thermal Impedance

Mechanical Dimensions

